

TOSHIBA FIELD EFFECT TRANSISTOR SILICON P CHANNEL JUNCTION TYPE

2SJ108

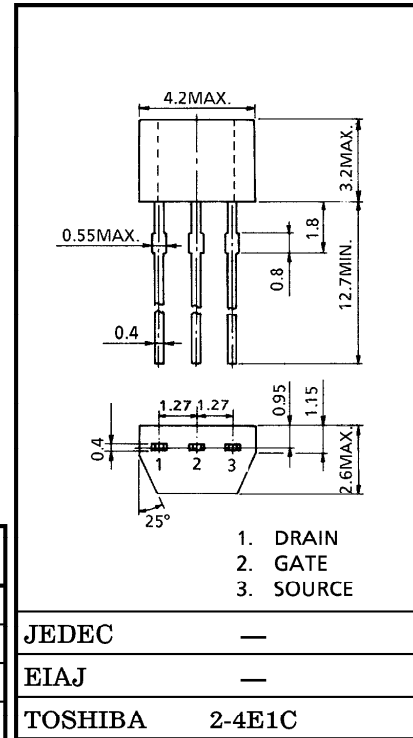
LOW NOISE AUDIO AMPLIFIER APPLICATIONS

Unit in mm

- Recommended for First Stages of EQ Amplifiers and MC Head Amplifiers.
- High $|Y_{fs}|$
: $|Y_{fs}| = 22\text{mS (Typ.) (}V_{DS} = -10\text{V, }V_{GS} = 0, I_{DSS} = -3\text{mA)}$
- Low Noise
: $E_n = 0.95\text{nV} / \sqrt{\text{Hz}} \text{ (Typ.) (}V_{DS} = -10\text{V, }I_D = -1\text{mA, }f = 1\text{kHz)}$
- High Input Impedance : $I_{GSS} = 1.0\text{nA (Max.) (}V_{GS} = 25\text{V)}$
- Complementary to 2SK370
- Small Package

MAXIMUM RATINGS ($T_a = 25^\circ\text{C}$)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Gate-Drain Voltage	V_{GDS}	25	V
Gate Current	I_G	-10	mA
Drain Power Dissipation	P_D	200	mW
Junction Temperature	T_j	125	$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-55~125	$^\circ\text{C}$



Weight : 0.13g (Typ.)

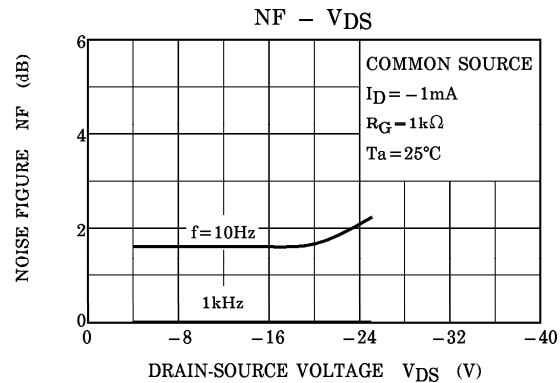
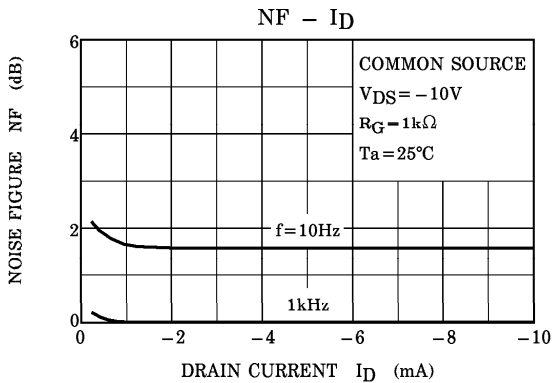
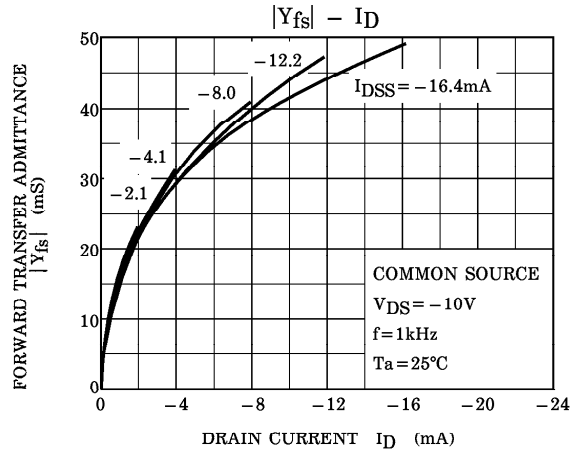
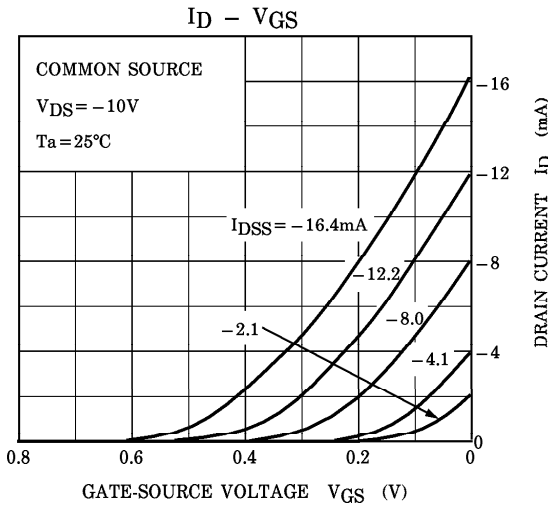
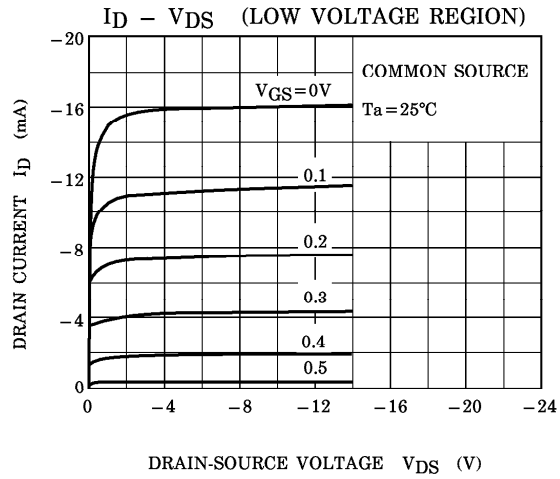
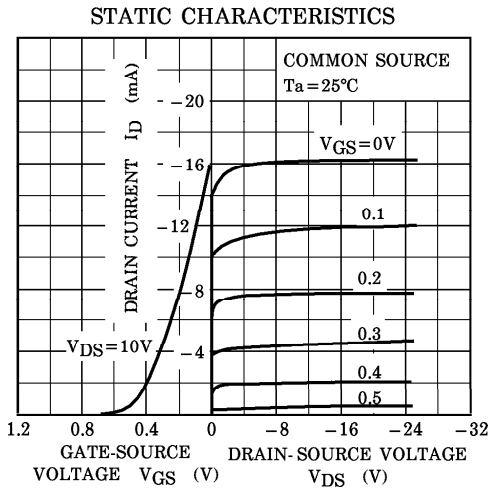
ELECTRICAL CHARACTERISTICS ($T_a = 25^\circ\text{C}$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Cut-off Current	I_{GSS}	$V_{GS} = 25\text{V, }V_{DS} = 0$	—	—	1.0	nA
Gate-Drain Breakdown Voltage	$V_{(BR)GDS}$	$V_{DS} = 0, I_G = 100\mu\text{A}$	25	—	—	V
Drain Current	I_{DSS} (Note)	$V_{DS} = -10\text{V, }V_{GS} = 0$	-2.6	—	-20	mA
Gate-Source Cut-off Voltage	$V_{GS(OFF)}$	$V_{DS} = -10\text{V, }I_D = -0.1\mu\text{A}$	0.15	—	2.0	V
Forward Transfer Admittance	$ Y_{fs} $	$V_{DS} = -10\text{V, }V_{GS} = 0, f = 1\text{kHz}$	8	22	—	mS
Input Capacitance	C_{iss}	$V_{DS} = -10\text{V, }V_{GS} = 0, f = 1\text{MHz}$	—	105	—	pF
Reverse Transfer Capacitance	C_{rss}	$V_{GD} = 10\text{V, }I_D = 0, f = 1\text{MHz}$	—	32	—	pF
Noise Figure	NF (1)	$V_{DS} = -10\text{V, }I_D = -1\text{mA, }R_G = 1\text{k}\Omega, f = 10\text{Hz}$	—	1.0	10	dB
	NF (2)	$V_{DS} = -10\text{V, }I_D = -1\text{mA, }R_G = 1\text{k}\Omega, f = 1\text{kHz}$	—	0.5	2	

Note : I_{DSS} Classification GR : -2.6~-6.5mA, BL : -6.0~-12mA, V : -10~-20mA

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